	Application No.	Applicant(s)
Notice of Allowability	10/809,999	WU ET AL.
	Examiner	Art Unit
	Theresa T. Doan	2814
The MAILING DATE of this communication appears on the cover sheet with the correspondence address All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS. This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.		
1. This communication is responsive to <u>03/26/04</u> .		
2. Mail The allowed claim(s) is/are 4-10.		•
3. The drawings filed on 26 March 2004 are accepted by the Examiner.		
 4. Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some* c) None of the: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No. 10/452,179. 3. Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)). ★ Certified copies not received: Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application. THIS THREE-MONTH PERIOD IS NOT EXTENDABLE. 5. A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF 		
INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient. 6. CORRECTED DRAWINGS (as "replacement sheets") must be submitted. (a) including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached 1) hereto or 2) to Paper No./Mail Date (b) including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).		
7. DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.		
 Attachment(s) 1. ☑ Notice of References Cited (PTO-892) 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948) 3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date	6. ☐ Interview Summary Paper No./Mail Dat 8), 7. ☐ Examiner's Amendr	e

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Reasons for Allowance

1. Claims 4-10 are allowed.

2. The following is an examiner's statement of reasons for allowance:

The prior art of record fails to disclose all the combination of a method for detecting the alignment of bit line contacts and active areas in DRAM devices recited in the base claims 4 and 7. Specifically, the combination of the process comprising providing a wafer with at least one scribe and at least one memory area; forming a plurality of memory cells in the memory area and at least one test device in the scribe line at the same time, wherein the memory area has bit line contacts and active areas, the test device including: a bar-type active area disposed in the scribe line, having a center, a predetermined width, and a predetermined resistivity; a bit line contact disposed on the center of bar-type active area; a bit line having a center coupled to the bit line contact, and a first terminal and a second terminal, wherein the bit line is essentially perpendicular to the bar-type active area; and two plugs disposed on the first terminal and the second terminal of the bar-type active area respectively, wherein the two plugs are electrically coupled to the first terminal and the second terminal of the bartype active area respectively; detecting a first resistance by the first terminal of the bit line and one of the two plugs; detecting a second resistance by the second terminal of the bit line and the other of the two plugs; determining whether the alignment of the bit line and the bar-type active area of the test device is normal according to the first resistance and the second resistance; and determining whether the alignment of the bit Application/Control Number: 10/809,999

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line contacts and the active areas in the memory areas is normal according to whether the alignment of the bit line contact and bar-type active area of the test device.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Theresa T. Doan whose telephone number is (571) 272-1704. The examiner can normally be reached on Monday to Friday from 7:00AM - 4:00PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, WAEL FAHMY can be reached on (571) 272-1705. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

TD June 24, 2005.

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